

Abstract Submitted
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Beam self-focusing in the near field emission scanning electron microscopy FUXIANG LI, ARTEM ABANOV — Recent experiment on the near field emission scanning electron microscopy shows an unexpectedly high lateral and vertical resolution. We show that these effects can be explained by the beams self-focusing. We derive the equations for the beam propagation and solve them numerically. Our results are in a very good agreement with the experiment.

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